

THREE REASONS TO TRUST THE MAP

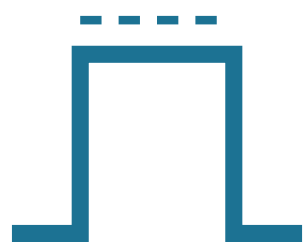
CALIBRATED UV STRESS / INSTRUMENT BASIS UNDER DEVELOPMENT

Poster PDF includes specs



Not just more UV — but a stress that is **uniform, high, and computed.**

01

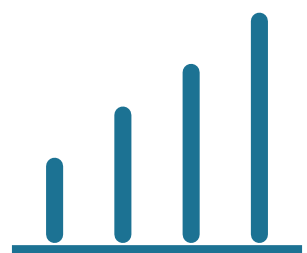


Uniform tophat beam

One intensity across the whole field, so one equivalent current density. That is what makes a cell colour mean “so many A/cm²”.

TOPHAT BEAM, 1 mm × 1 mm / 2 mm × 2 mm

02



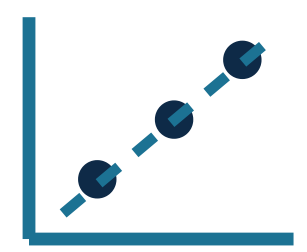
Up to 2,000–3,000 A/cm² equivalent

Reaches stress levels that are hard to apply in burn-in, and steps through them in one run so each site is graded by the level it withstood.

Th-P-80 Oct 1, 15:00–17:00 · Poster-C (4th Floor, G403+G404)
On the Critical Threshold for the Expansion of a Single Shockley-Type Stacking Fault in n-Type 4H-SiC
ITES : Yasuyuki Igarashi

PULSED UV LASER, 355 nm / up to 20 W

03



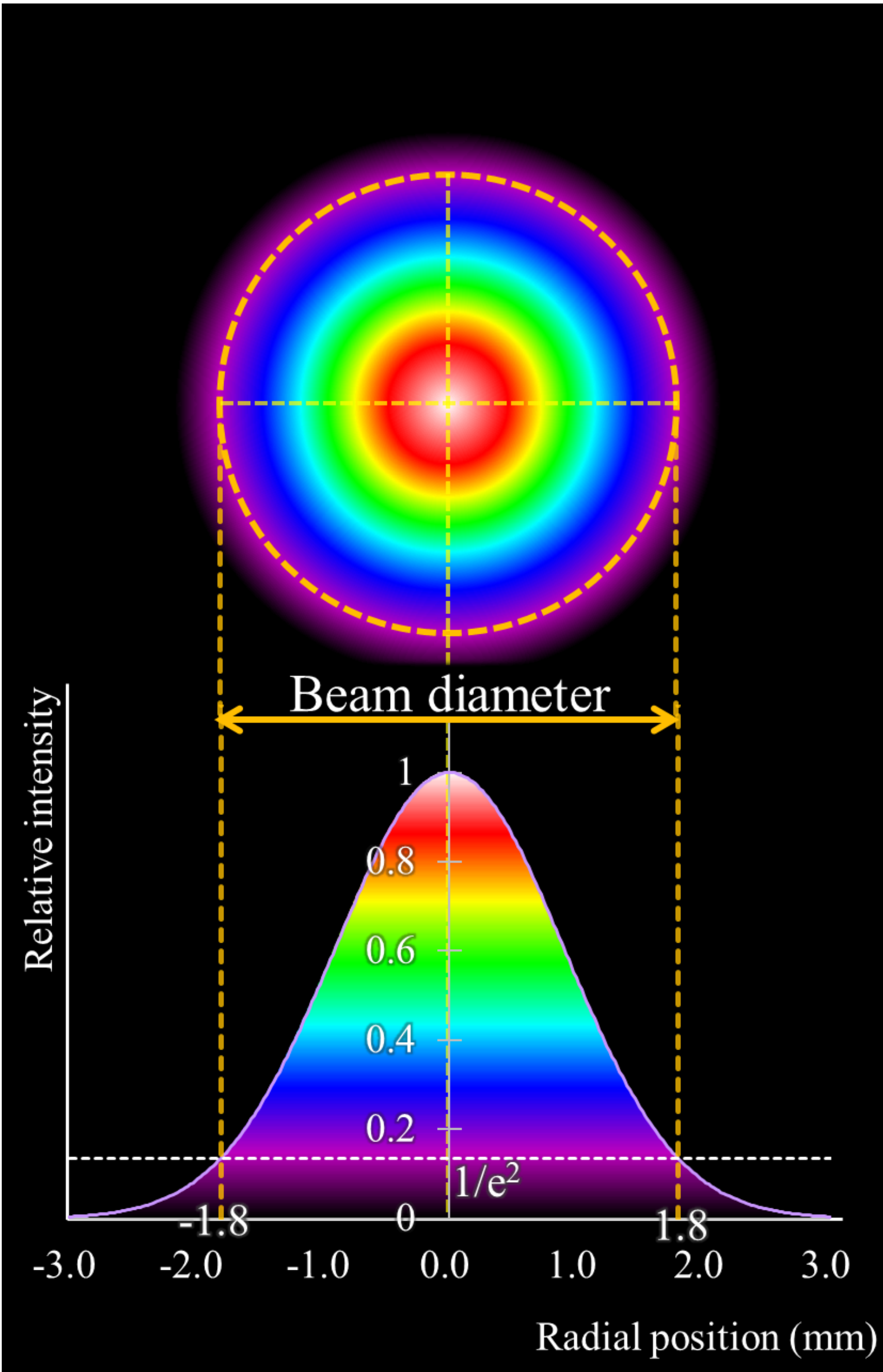
Conditions computed from a current value

Layer stack and the current density your device runs at go in; the UV condition that matches comes out. Measured backing is available as a calibration report.

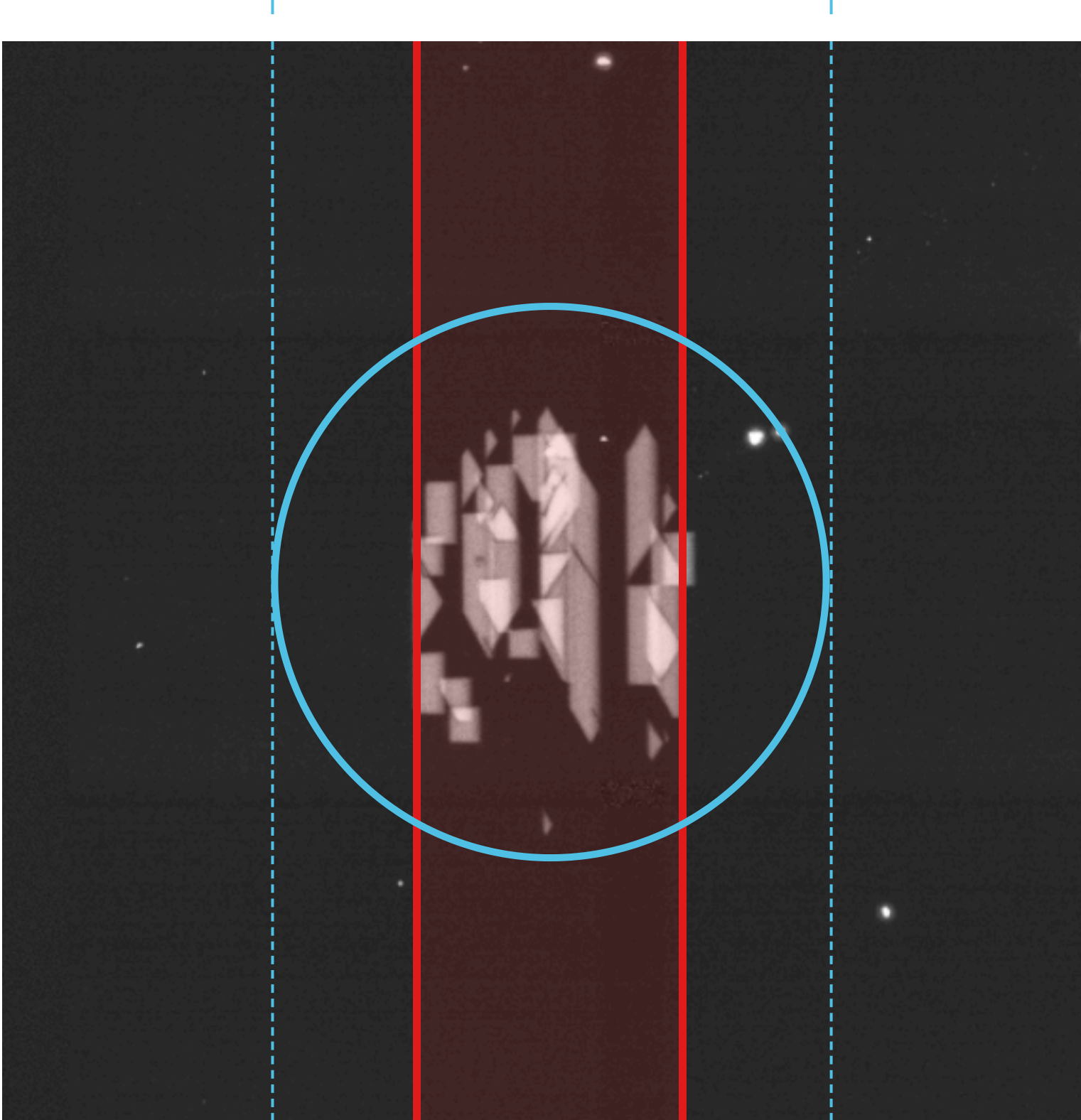
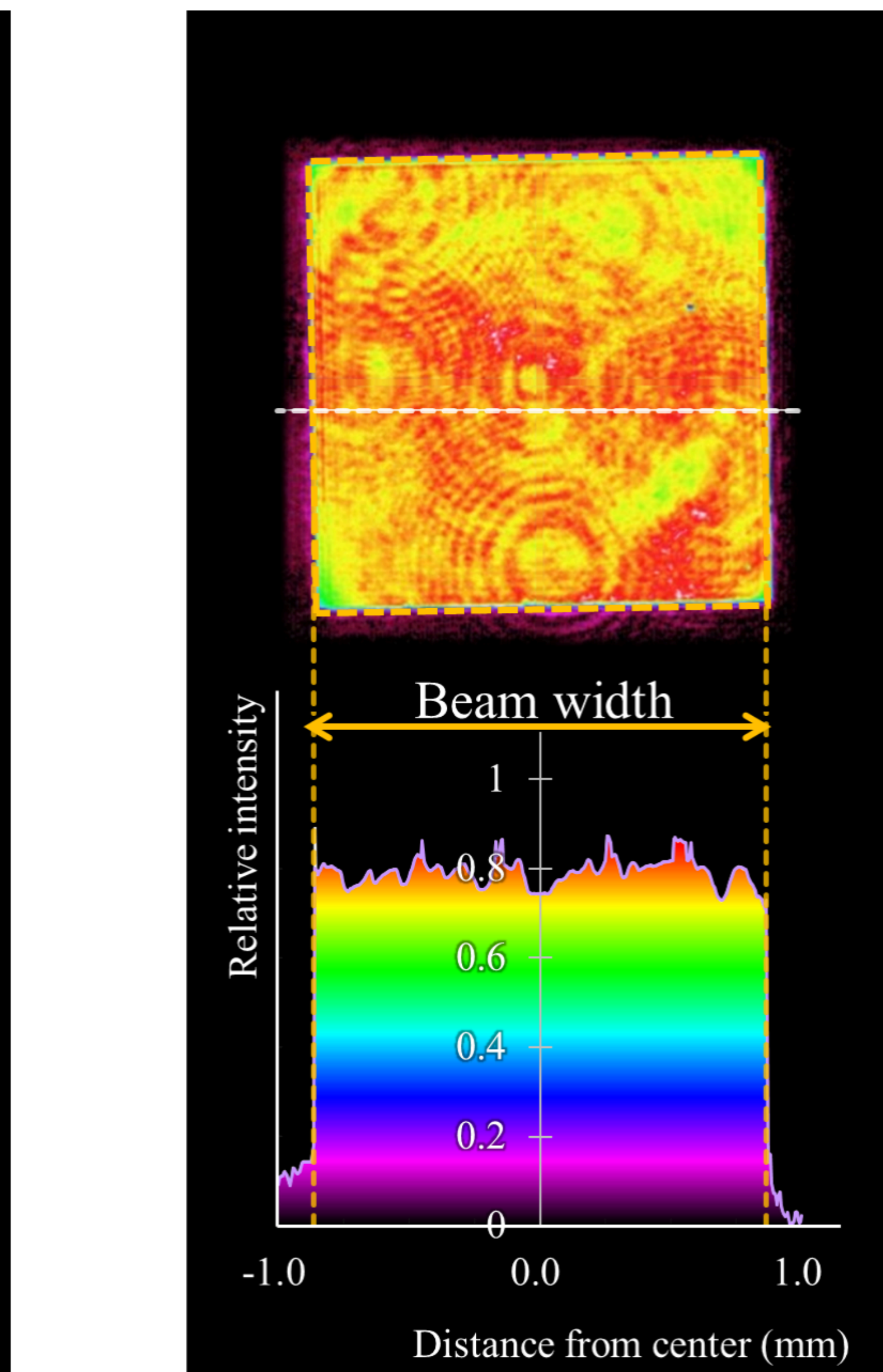
RECIPE HELD PER RUN / WAFER / SITE

BEAM PROFILE / 355 nm PL after UV stress at the same nominal power

GAUSSIAN



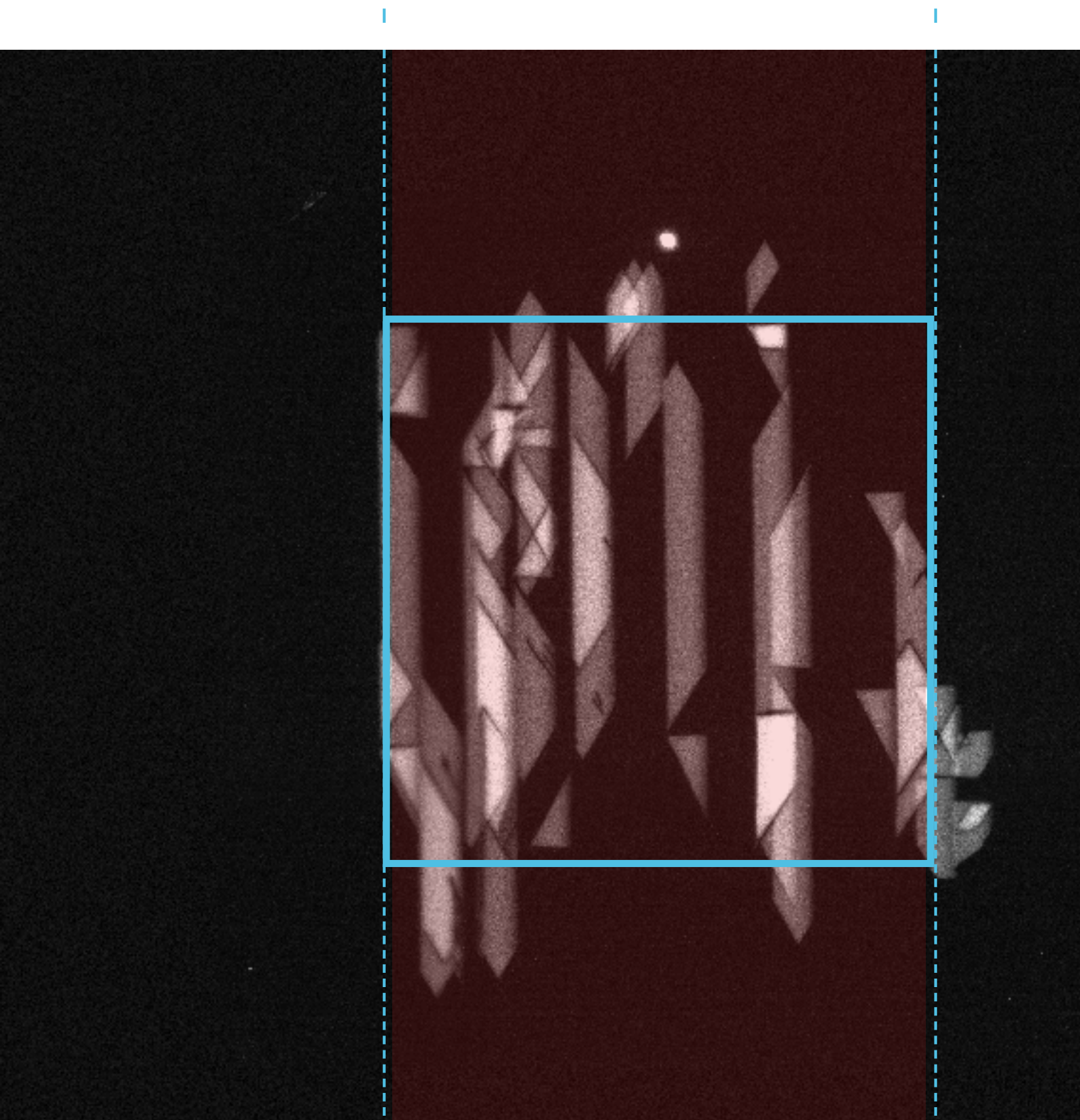
TOP-HAT



EXPANDS

Intensity differs by position, so no single A/cm² can be assigned.

Only the peak passes the threshold, so a narrow central band expands.



EXPANDS

One intensity everywhere, so one equivalent current density everywhere.

Expansion runs across the full beam width, not only at a centre peak.

— Beam width / irradiated area — Area that contributes to expansion

SPECIFICATIONS

Samples	4H-SiC epi / substrate, 6 and 8 inch
UV source	Pulsed UV laser, 355 nm
Beam	Tophat, 1 mm × 1 mm / 2 mm × 2 mm
Equivalent stress	Up to 2,000–3,000 A/cm ²
PL objectives	2.5× / 5× / 10×
Stage	Shared XYθ for stress and imaging, KLA-compatible coordinates

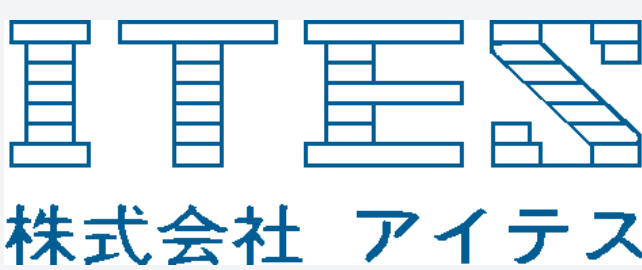
THE INSTRUMENT



UV stress and PL imaging on one stage

Ask us for the calibration report behind any colour on the map.

Origin classification and depth analysis — take the leaflet.



Specifications are to be finalised in design verification. Equivalent current density figures are development data under review.